USING TDL FOR STANDARDISED TEST PURPOSE DEFINITIONS





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OUTLINE



- Our Context
- ETSI Testing approach
 - TDL
 - TTCN-3
- Application samples within ETSI
 - TC INT projects
 - TC MTS standardisation











- ETSI is a leading <u>standardisation organisation</u> for Information and Communication Technology (ICT) standards fulfilling European and global market needs.
- ETSI test specifications are developed according to the well-proven methodology defined in ISO/IEC 9646.
 This <u>framework</u> recommends that the test specifications include:

Test Purposes, Test Descriptions and Test Cases.





ETSI TC MTS

- > Technical Committee "Methods for Testing and Specification"
- Working Group TDL provides and oversees roadmap for further development of TDL and the TDL open source project
- Working Group TST develops IoT test catalogues and specifications (not covered elsewhere)
 - The **types of testing** include conformance, interoperability, security and performance testing
 - The initial technical **focus** is:
 - loT network layer (communication protocols, node connectivity, edge computing etc.),
 - Basic security of IoT devices



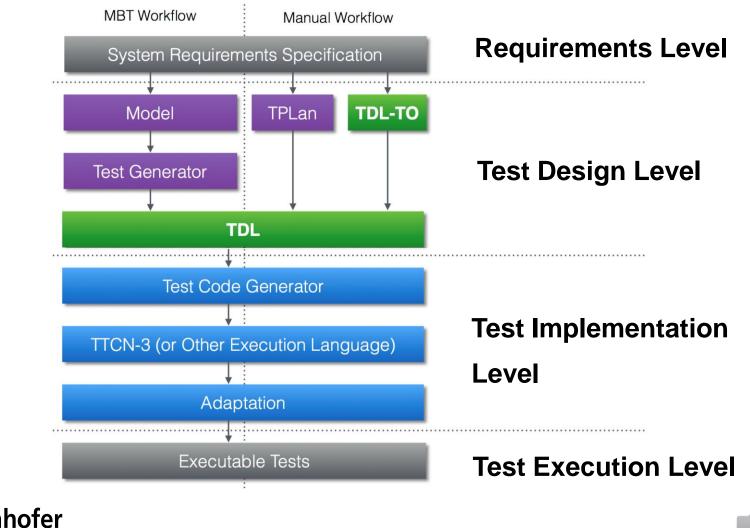






ETSI TESTING APPROACH

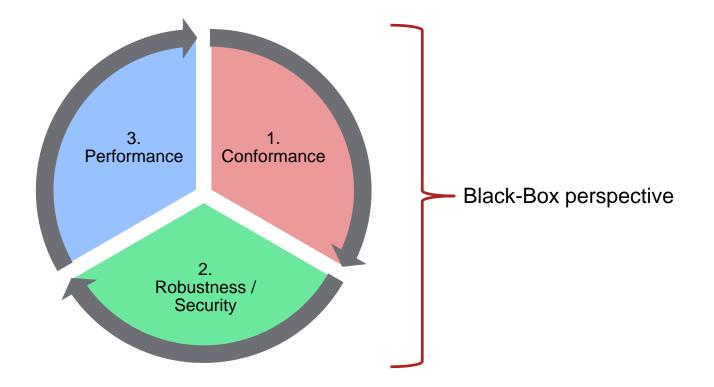
TEST DESCRIPTION LANGUAGE





QUALITY ASPECTS









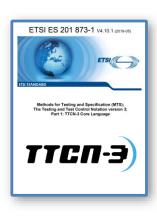
ETSI TEST LANGUAGE STANDARDS

Test Description Language

- Design, documentation, representation of formalised test descriptions
- Scenario-based approach

Testing and Test Control Notation

- Specification and implementation of all kinds of black-box tests
- Component-based approach











TEST PURPOSE SPECIFICATION, SAMPLE MQTT



- 1) Test configurations
- 2) Test Suite Structure
- 3) Test purpose (catalogue)
- 4) Test implementation (TTCN-3)

TP Id	TP_MQTT_Broker_CONNECT_001				
Test Objective	The IUT MUST close the network connection if fixed header flags in CONNECT Control Packet are invalid				
Reference	[MQTT-2.2.2-1], [MQTT-2.2.2-2], [MQTT-3.1.4-1], [MQTT-3.2.2-6]				
PICS Selection	PIC_BROKER_BASIC				
Initial Conditions					

Expected Behaviour

ensure that {
 when {
 the IUT receives a CONNECT message containing
 header_flags indicating value '1111'B;
 } then {
 the IUT closes the TCP_CONNECTION
 }
}
Final Conditions





TDL-TO – TEST OBJECTIVE SPECIFICATION



- Informal text specification (semi-structured)
- Simple description structure (event occurrence sequences)
- Global keyword definitions
 (domain specific)
- Single test observation (for pass/fail verdict criteria)





TTCN-3 – THE TEST EXECUTION LANGUAGE

1) Test configurations

2) Test Suite Structure

3) Test purpose (catalogue)

4) Test implementation (TTCN-3)

Did you know that YOUR PHONE...











APPLICATION: INTEROPERABILITY TESTS



- Technical Committee "Core Network and Interoperability Testing (INT)"
- Specialist/Testing Task Forces on "Voice and video services over LTE"
 - ✓ For multiple interfaces of the identified test configurations
 - Packages with common
 domain definitions (library concept)
 - ✓ More than 300 TDL-TO test purposes
 - ✓ TDL Open Source Project (TOP) tools

Configuration { Interface Type defaultGT accepts DiameterMessage; Component Type DiameterComp with gate g of type defaultGT

Test Configuration CF_VxLTE_INT containing SUT component EPC_PGW_A of type DiameterComp SUT component EPC_PCRF_A of type DiameterComp SUT component S_CSCF_A of type DiameterComp SUT component I_CSCF_A of type DiameterComp SUT component P_CSCF_A of type DiameterComp SUT component HSS_A of type DiameterComp SUT component EPC_MME_A of type DiameterComp SUT component IMS_AS_A of type DiameterComp SUT component IMS_AS_A of type DiameterComp connection between EPC_MME_A.g and HSS_A.g connection between EPC_PGW_A.g and EPC_PCRF_A.g connection between HSS_A.g and S_CSCF_A.g connection between HSS_A.g and I_CSCF_A.g connection between IMS_AS_A.g and HSS_A.g

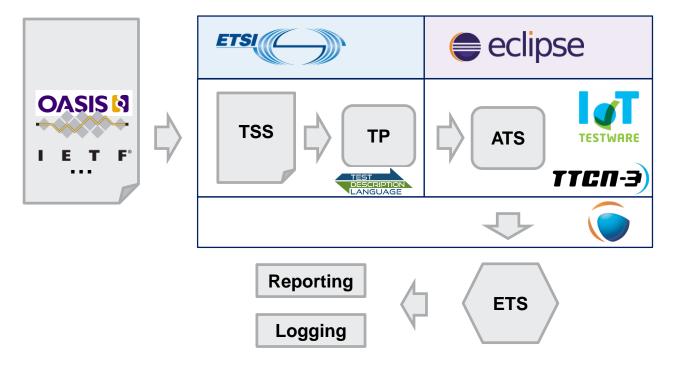
Test Configuration CF_VxLTE_RMI containing SUT component EPC_PGW_B of type DiameterComp SUT component EPC_PCRF_A of type DiameterComp SUT component EPC_PCRF_B of type DiameterComp SUT component P_CSCF_B of type DiameterComp SUT component HSS_A of type DiameterComp SUT component EPC_MME_B of type DiameterComp connection between EPC_MME_B.g and HSS_A.g connection between EPC_PGW_B.g and EPC_PCRF_B.g connection between EPC_PCRF_A.g and EPC_PCRF_B.g connection between EPC_PCRF_B.g and P_CSCF_B.g

Fraunhofer

}// End of Configuration section

APPLICATION: IOT-TESTWARE – THE TWO PILLARS





Legend: TP: Test Purpose TSS: Test Suite Structure

ATS: Abstract Test Suite ETS: Executable Test Suite SUT: System Under Test





Work Item Monitoring - MTS TST							
7 Wis, W	/ork in progres	s, displaying 1 to 7	Disp	lays 30 🗸]		
Work item number	Version	Current status	Next status	Rapporteur name			
MTS TST							
DTS/MTS-TST8 (TS 103 646)	å 0.1.1	I TB approval (2020-11-02)	Draft receipt by ETSI Secretariat	Hackel Sascha	IEC 62443-4-2		
DTS/MTS-TSTCoAP-1 (TS 103 596-1)	🛓 0.1.1	Stable draft (2020-09-07)	Final draft for approval	Hackel Sascha			
DTS/MTS-TSTCoAP-2 (TS 103 596-2)	≜ 0.1.0	Stable draft (2020-09-08)	Final draft for approval	Hackel Sascha	СоАР		
DTS/MTS-TSTCoAP-3 (TS 103 596-3)	a 0.1.0	WG approval (2020-11-20)	TB approval	Gheorghe-Pop Ilie-Daniel			
DTS/MTS-TSTMQTT-1 (TS 103 597-1)	a 0.1.2	I TB approval (2020-11-02)	Draft receipt by ETSI Secretariat	Pintar Bostjan			
DTS/MTS-TSTMQTT-2 (TS 103 597-2)	a 0.1.0	Stable draft (2020-09-04)	Final draft for approval	Pintar Bostjan	MQTT		
DTS/MTS-TSTMQTT-3 (TS 103 597-3)	a 0.1.4	MG approval (2020-11-20)	TB approval	Gheorghe-Pop Ilie-Daniel			

https://portal.etsi.org/tb.aspx?tbid=860&SubTB=860





TEST DESCRIPTION LANGUAGE

BENEFITS OF TDL AS A TEST SPECIFICATION LANGUAGE

- ✓ Abstract → Keeps you focused on what to test
- ✓ Standardised → Helps you to produce *repeatable* results independently from a chosen certain tool or tool provider



- ✓ Application focus → Wide range of features for today's interconnected, concurrent, embedded, real-time systems
- ✓ Semi-formal → Helps you to keep test specifications consistent over evolving systems (meta-modelling supported static code analysis)
- ✓ Multiple syntaxes → Provide test specifications in a language that different stakeholders understand best (graphical, textual, other)
- ✓ Tool support → The TDL Open source Project (TOP) offers tool support for the use of TDL





SUMMARY & OUTLOOK

- ✓ Standardised test purposes
 - Used in multiple <u>domains</u>:
 e.g. mobile, access/core networks, ITS
 - Test types, e.g. conformance, interop, security
- ✓ Advanced testing technology:
 - Used for <u>certification</u>:
 e.g. UMTS, LTE, 5G, oneM2M
- ✓ ETSI continues maintenance and evolution
 - TDL: https://tdl.etsi.org/
 - TTCN-3: http://www.ttcn-3.org/















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Thank you for your attention!

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